


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521620	<b>Applicant(s)/Patent Under Reexamination</b>  HEUER ET AL.
	<b>Examiner</b>  Lewis, Cheryl	<b>Art Unit</b>  2167

SEARCHED			
Class	Subclass	Date	Examiner
707	100, 101, and 200	1/2/2009	CL

SEARCH NOTES		
Search Notes	Date	Examiner
searched WEST US Patents, Pre-Grant Publications database, JPO Abstracts, and EPO Abstracts	1/2/2009	CL
searched Derwent Patents and IBM Disclosure	1/2/2009	CL
searched ACM Library and Google Scholar	1/2/2009	CL
text searched class: 707 and subclasses: 100, 101, and 200	1/2/2009	CL
Inventor Name Search	1/2/2009	CL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
same as	above	1/2/2009	CL

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